

# Juntu Feng

## List of Publications by Year in descending order

Source: <https://exaly.com/author-pdf/6882384/publications.pdf>

Version: 2024-02-01

3  
papers

44  
citations

2682572

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2917675

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docs citations

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times ranked

68  
citing authors

#	ARTICLE	IF	CITATIONS
1	Degradation Behavior and Mechanisms of E-Mode GaN HEMTs With p-GaN Gate Under Reverse Electrostatic Discharge Stress. IEEE Transactions on Electron Devices, 2020, 67, 566-570.	3.0	30
2	Trap Analysis Based on Low-Frequency Noise for SiC Power MOSFETs Under Repetitive Short-Circuit Stress. IEEE Journal of the Electron Devices Society, 2020, 8, 145-151.	2.1	12
3	The ESD Behavior of Enhancement GaN HEMT Power Device with p-GaN Gate Structure. , 2018, , .		2